

IN THE SPECIFICATION:

Please replace the Title of the Disclosure currently on file with the following:

SEMICONDUCTOR INTEGRATED CIRCUIT HAVING SELF-TESTING CIRCUIT AND METHOD FOR DESIGNING THE SAME

Please replace page 16, paragraph 2, of the Disclosure currently on file with the following paragraph:

b1
Next, the write data is read from the memory array 11 (step S13). The read data is amplified by the sense amplifier 13 and supplied to the input/output & comparator 20. At this time, the write data that is input when the data is written is input to the data input/output terminal 42+. Accordingly, the input/output & comparator 20 compares the data read from the memory array 11 with the write data input to the data input/output terminal 42+ and outputs the comparison result signal CM indicating a match or mismatch to the write control circuit 34 of the variable address conversion circuit 30.